

## CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

# A2 Global Electronics + Solutions (America II Europe B.V.)

Rijnlanderweg 766, Unit C 2132NM Hoofddorp, The Netherlands

Fulfills the requirements of

**ISO/IEC 17025:2017** 

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

### **TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at <a href="www.anab.org">www.anab.org</a>.

Jason Stine, Vice President

Expiry Date: 22 December 2027 Certificate Number: AT-3054.02









#### SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

# A2 Global Electronics + Solutions (America II Europe B.V.)

Rijnlanderweg 766, Unit C 2132NM Hoofddorp, The Netherlands Tony Giannetti +1 800 767 2637 x1043

#### **TESTING**

ISO/IEC 17025 Accreditation Granted: 11 December 2025

Certificate Number: AT-3054.02 Certificate Expiry Date: 22 December 2027

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics** + **Solutions** to perform the following AS6171 slash sheet tests:

#### **Non-Destructive Testing**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2		Multiple Microscopes
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2		Mineral spirits, Isopropyl alcohol, Acetone
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2	Electrical, Electronic and Electromechanical (EEE)	Digital Calipers, Auto Contactless Measurement
XRF	AS6081, 4.2.6.4.5 AS6171/3	Components	Multiple X-ray Fluorescence Testing Equipment
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testing Equipment

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#### **Non-Destructive Testing**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Pr <mark>o</mark> duct Tested	Key Equipment or Technology
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6	Electrical, Electronic and	Scanning Acoustic Microscope (SAM)
Scanning Electron Microscopy (SEM) Examination/Inspection	AS6171/2 AS6081 4.2.6.4.3 C	Electromechanical (EEE) Components	Scanning Electron Microscope (SEM)

#### Mechanical

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Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Furnace acid less oven
Solderability	ANSI/J-STD-002		Solder Pot Reflow Oven
Wetting Balance Solder	ANSI/ <mark>J-STD-002</mark> MIL-STD-883		Wetting Balance Tester
Plating Thickness	AS6171/3		Plating Thickness Tester
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2		Hot Plate, Multiple Chemicals

#### Electrical

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Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Section C.3		
DC Test and Key Parameters (AC, Switching, Functional), Over Temperature		Electrical, Electronic and Electromechanical (EEE)	ATE and Various Electronic Lab Equipment
DC Test and Key Parameters (AC, Switching, Functional), Ambient Temperature	Δ \	Components	



This Scope of Accreditation, version 005, was last updated on: 11 December 2025 and is valid only when accompanied by the Certificate.



